



PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. <b>219.005-C1-US</b>	SERIAL NUMBER <b>10/790,276</b>
	APPLICANT(S) <b>Yamada et al.</b>	
	FILING DATE <b>March 1, 2004</b>	GROUP ART UNIT <b>2825-2125</b>

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
Qh n	4,571,685	2/1986	Kamoshida	—	—	
Q. P	6,055,463	4/2000	Cheong et al.	—	—	
Q. P	6,314,379	11/2001	Hu et al.	—	—	
Q. P	6,338,001	1/2002	Steffan et al.	—	—	
Qh r	6,542,830	4/2003	Mizuno et al.	—	—	

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER <i>Albert W. Palmer</i>	<b>ALBERT W. PALMER</b> PATENT EXAMINER	DATE CONSIDERED <b>9-14-04</b>
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Arr	3,614,608	10/1971	Giedd	—	—	
Arr	4,949,162	8/1990	Tamaki et al.	—	—	
Arr	4,988,877	1/1991	Stokowski et al.	—	—	
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Arr	5,089,774	2/1992	Nakano	—	—	
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Arr	5,280,176	1/1994	Jach et al.	—	—	
Arr	5,327,012	7/1994	Yano et al.	—	—	
Arr	5,365,034	11/1994	Kawamura et al.	—	—	
Arr	5,412,210	5/1995	Todokoro et al.	—	—	
Arr	5,453,994	9/1995	Kawamoto et al.	—	—	
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Arr	5,637,186	6/1997	Liu et al.	—	—	
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EXAMINER <i>Albert W. Paladini</i>	ALBERT W. PALADINI PATENT EXAMINER	DATE CONSIDERED 9-14-04
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PTO (Patent and Trademark Office)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. <b>219.005-C1-US</b>	SERIAL NUMBER <b>10/790,276</b>
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## FOREIGN PATENT DOCUMENTS

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AWP	04-062857	2/1992	Japan	—	—		
AWP	06-273297	9/1994	Japan	—	—		
AWP	07-088172	3/1995	Japan	—	—		
AWP	08-005528	1/1996	Japan	—	—	Y	
AWP	08-313244	11/1996	Japan	—	—		
AWP	09-061142	3/1997	Japan	—	—	Y	
AWP	10-281746	10/1998	Japan	—	—		
AWP	10-300450	11/1998	Japan	—	—		
AWP	11-026343	1/1999	Japan	—	—		
AWP	2000-164715	6/2000	Japan	—	—		
AWP	2000-180143	6/2000	Japan	—	—		
AWP	2000-124276	4/2000	Japan	—	—		
AWP	2000-174077	6/2000	Japan	—	—		

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

AWP

ALBERT W. PALADIN  
PATENT EXAMINER

DATE CONSIDERED

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Bul	50-63990	5/1975	Japan	—	—	Y
air	57-6310	1/1982	Japan	—	—	Y
air	62-19707	1/1987	Japan	—	—	Y
air	63-9807	1/1988	Japan	—	—	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	"An In-Line Contact and Via Hole Inspection Method Using Electron Beam Compensation Current", Yamada et al., IEEE 1999, Doc. No. 0-7803-5413-3/99, available from <a href="http://www.fabsol.com/us/images/library/21.pdf">http://www.fabsol.com/us/images/library/21.pdf</a>

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